Notice of References Cited Application/Control No. 10/646,605 Examiner Ashford S. Hayles Applicant(s)/Patent Under Reexamination VITULLI ET AL. Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,847,728 A	12-1998	Lee, Yong-duk	347/33
*	В	US-5,953,707 A	09-1999	Huang et al.	705/10
*	С	US-6,151,582 A	11-2000	Huang et al.	705/8
*	D	US-6,154,728 A	11-2000	Sattar et al.	705/28
*	Е	US-6,295,423 B1	09-2001	Haines et al.	399/24
*	F	US-2002/0005874 A1	01-2002	Imai et al.	347/33
*	G	US-6,341,271 B1	01-2002	Salvo et al.	705/28
*	Ι	US-6,390,582 B1	05-2002	Laharaty et al.	347/14
*	-	US-2002/0054316 A1	05-2002	Abe, Yoshinori	358/1.14
*	J	US-2002/0072998 A1	06-2002	Haines et al.	705/28
*	K	US-2002/0143642 A1	10-2002	Harper, Mark A.	705/26
*	L	US-6,556,926 B1	04-2003	Haines, Robert E.	702/34
*	М	US-2003/0065972 A1	04-2003	Yamamoto et al.	714/4

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/646,605 Examiner Ashford S. Hayles Applicant(s)/Patent Under Reexamination VITULLI ET AL. Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0074428 A1	04-2003	Haines, Robert E.	709/220
*	В	US-2003/0093388 A1	05-2003	Albright, Brian	705/400
*	С	US-2003/0101107 A1	05-2003	Agarwal et al.	705/28
*	D	US-2003/0135431 A1	07-2003	Schwartz et al.	705/28
*	Е	US-2003/0139982 A1	07-2003	Schwartz et al.	705/28
*	F	US-2003/0154144 A1	08-2003	Pokorny et al.	705/28
*	G	US-2003/0158795 A1	08-2003	Markham et al.	705/28
*	Н	US-2003/0172072 A1	09-2003	Smith, Margaret Paige	707/10
*	ı	US-6,629,134 B2	09-2003	Hayward et al.	709/217
*	J	US-2003/0220711 A1	11-2003	Allen, Barry	700/215
*	K	US-2004/0024659 A1	02-2004	Mathew et al.	705/28
*	L	US-2004/0103048 A1	05-2004	Vitulli et al.	705/028
*	М	US-2004/0153187 A1	08-2004	Knight et al.	700/099

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

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A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/646,605 Examiner Ashford S. Hayles Applicant(s)/Patent Under Reexamination VITULLI ET AL. Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,798,997 B1	09-2004	Hayward et al.	399/12
*	В	US-6,868,397 B1	03-2005	McCaslin, Thomas W.	705/28
*	С	US-6,866,195 B2	03-2005	Knowles et al.	235/385
*	D	US-2005/0102203 A1	05-2005	Keong, Koh Soo	705/028
*	Е	US-6,934,862 B2	08-2005	Sharood et al.	713/300
*	F	US-6,996,538 B2	02-2006	Lucas, Michael T.	705/28
*	G	US-7,013,092 B2	03-2006	Hayward et al.	399/24
*	Ι	US-7,031,933 B2	04-2006	Harper, Mark A.	705/26
*	-	US-7,099,026 B1	08-2006	Hren, Allan Anthony	358/1.15
*	J	US-7,225,981 B2	06-2007	Jongebloed, Kenneth William	235/385
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.